## Applicant(s)/Patent Under Application/Control No. Reexamination 10/647,725 DUFF ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2623 Jason K. Lin **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 725/153 05-2004 Del Castillo, Leonardo US-6,742,188 Α 386/83 Yuen et al. 12-2003 US-6,668,133 В 725/136 09-2005 Ranta et al. С US-2005/0204400 725/153 Koplar et al. US-2002/0112250 08-2002 D US-Ε US-F US-G USн US-US-J Κ US-US-L US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U V W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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